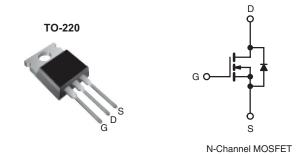




Power MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	10	100			
R _{DS(on)} (Ω)	V _{GS} = 10 V	0.077			
Q _g (Max.) (nC)	7	2			
Q _{gs} (nC)	1	1			
Q _{gd} (nC)	3	32			
Configuration	Sin	Single			



FEATURES

- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- 175 °C Operating Temperature
- · Fast Switching
- · Ease of Paralleling
- · Simple Drive Requirements
- Lead (Pb)-free Available

DESCRIPTION

Third generation Power MOSFETs from Vishay provide the designer with the best combination of fast switching, ruggedized device design, low on-resistance and cost-effectiveness.

The TO-220 package is universally preferred for all commercial-industrial applications at power dissipation levels to approximately 50 W. The low thermal resistance and low package cost of the TO-220 contribute to its wide acceptance throughout the industry.

ORDERING INFORMATION		
Package	TO-220	
Lead (Pb)-free	IRF540PbF	
Lead (Fb)-liee	SiHF540-E3	
SnPb	IRF540	
JIII U	SiHF540	

PARAMETER	SYMBOL	LIMIT	UNIT	
Drain-Source Voltage	V _{DS}	100	V	
Gate-Source Voltage	V_{GS}	± 20	V	
Continuous Drain Current	V_{GS} at 10 V $T_{C} = 25 ^{\circ}C$ $T_{C} = 100 ^{\circ}C$		28	А
	T _C = 100 °C	l _D	20	
Pulsed Drain Current ^a	I _{DM}	110	1	
Linear Derating Factor		1.0	W/°C	
Single Pulse Avalanche Energy ^b	E _{AS}	230	mJ	
Repetitive Avalanche Current ^a	I _{AR}	28	Α	
Repetitive Avalanche Energy ^a	E _{AR}	15	mJ	
Maximum Power Dissipation	T _C = 25 °C	P _D	150	W
Peak Diode Recovery dV/dtc	dV/dt	5.5	V/ns	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to + 175	°C	
Soldering Recommendations (Peak Temperature)	for 10 s		300 ^d	
Mounting Torque	6 20 or M2 corour		10	lbf ⋅ in
	6-32 or M3 screw	Ī	1.1	N·m

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. V_{DD} = 25 V, starting T_J = 25 °C, L = 440 μ H, R_G = 25 Ω , I_{AS} = 28 A (see fig. 12).
- c. $I_{SD} \leq$ 28 A, $dI/dt \leq$ 170 A/ μ s, $V_{DD} \leq$ V_{DS} , $T_{J} \leq$ 175 °C.
- d. 1.6 mm from case.

^{*} Pb containing terminations are not RoHS compliant, exemptions may apply

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THERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	62	
Case-to-Sink, Flat, Greased Surface	R _{thCS}	0.50	-	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	1.0	

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT
Static							
Drain-Source Breakdown Voltage	V _{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$		100	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	Reference to 25 °C, I _D = 1 mA		-	0.13	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$		2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
Zana Onto Walle and David Onesant		V _{DS} = 100 V, V _{GS} = 0 V		-	-	25	,
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 80 V, V	_{GS} = 0 V, T _J = 150 °C	-	-	250	μΑ
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 17 A ^b	-	-	0.077	Ω
Forward Transconductance	9 _{fs}	V _{DS} = 50 V, I _D = 17 A ^b		8.7	-	-	S
Dynamic							
Input Capacitance	C _{iss}	$V_{GS} = 0 \text{ V},$ $V_{DS} = 25 \text{ V},$ $f = 1.0 \text{ MHz}, \text{ see fig. 5}$		-	1700	-	pF
Output Capacitance	C _{oss}			ı	560	-	
Reverse Transfer Capacitance	C _{rss}			-	120	-	
Total Gate Charge	Qg	$V_{GS} = 10 \text{ V}$ $I_D = 17 \text{ A}, V_{DS} = 80 \text{ V}, - \frac{1}{2}$ see fig. 6 and 13 ^b		-	-	72	
Gate-Source Charge	Q_{gs}		ı	-	11	nC	
Gate-Drain Charge	Q_{gd}		see lig. 6 and 13°	-	-	32	1
Turn-On Delay Time	t _{d(on)}	$V_{DD} = 50 \text{ V, } I_D = 17 \text{ A}$ $R_G = 9.1 \ \Omega, \ R_D = 2.9 \ \Omega, \ \text{see fig. } 10^b$		-	11	-	- ns
Rise Time	t _r			-	44	-	
Turn-Off Delay Time	t _{d(off)}			-	53	-	
Fall Time	t _f			-	43	-	
Internal Drain Inductance	L_D	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	-11
Internal Source Inductance	L _S			-	7.5	-	- nH
Drain-Source Body Diode Characteristic	s						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the integral reverse p - n junction diode		-	-	28	- A
Pulsed Diode Forward Current ^a	I _{SM}			-	-	110	
Body Diode Voltage	V_{SD}	T _J = 25 °C, I _S = 28 A, V _{GS} = 0 V ^b		-	-	2.5	٧
Body Diode Reverse Recovery Time	t _{rr}	T _J = 25 °C, I _F = 17 A, dl/dt = 100 A/μs ^b		ı	180	360	ns
Body Diode Reverse Recovery Charge	Q_{rr}			-	1.3	2.8	μC
Forward Turn-On Time	t _{on}	Intrinsic turn-	on is dor	ninated b	v Ls and	L _D)	

Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b. Pulse width $\leq 300~\mu s;$ duty cycle $\leq 2~\%.$



TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

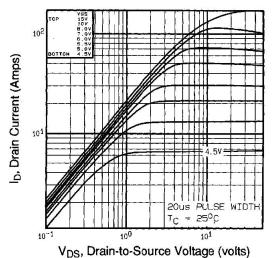


Fig. 1 - Typical Output Characteristics, T_C = 25 °C

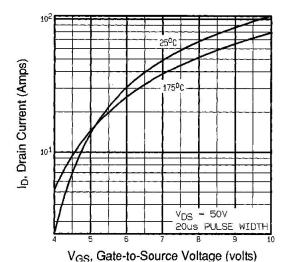


Fig. 3 - Typical Transfer Characteristics

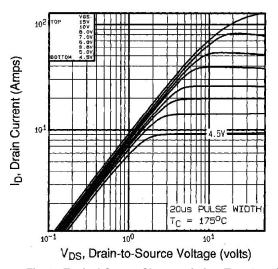


Fig. 2 - Typical Output Characteristics, T_C = 175 $^{\circ}C$

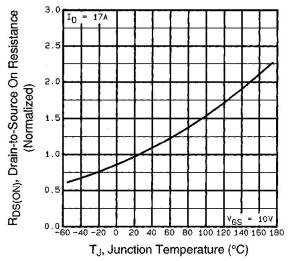


Fig. 4 - Normalized On-Resistance vs. Temperature

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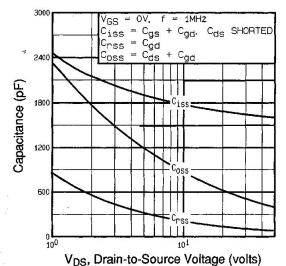


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

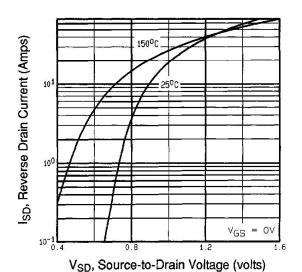


Fig. 7 - Typical Source-Drain Diode Forward Voltage

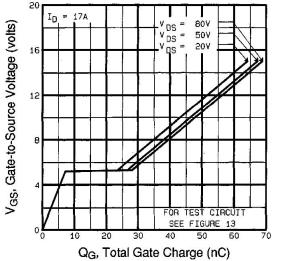


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

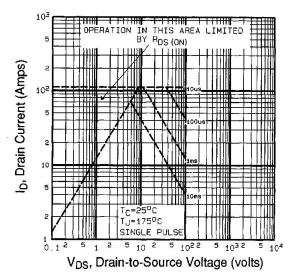
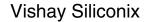


Fig. 8 - Maximum Safe Operating Area





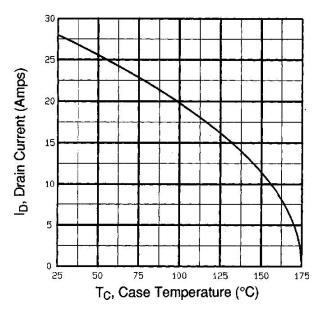


Fig. 9 - Maximum Drain Current vs. Case Temperature

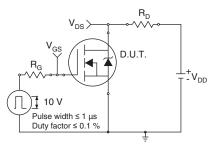


Fig. 10a - Switching Time Test Circuit

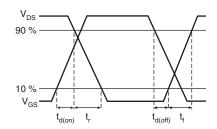


Fig. 10b - Switching Time Waveforms

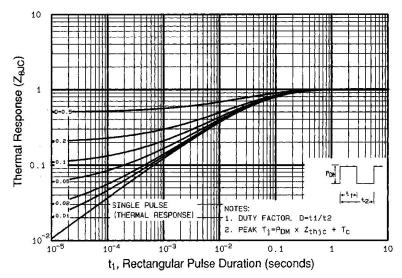


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

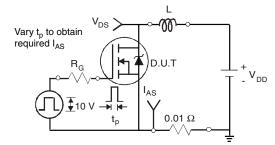


Fig. 12a - Unclamped Inductive Test Circuit

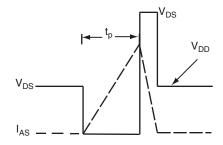


Fig. 12b - Unclamped Inductive Waveforms

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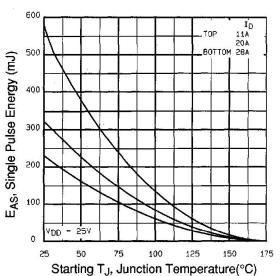


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

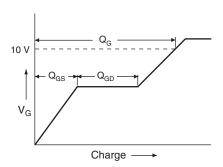


Fig. 13a - Basic Gate Charge Waveform

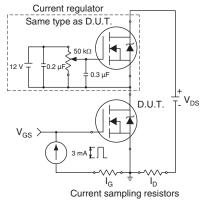
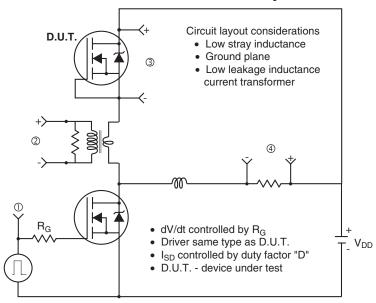
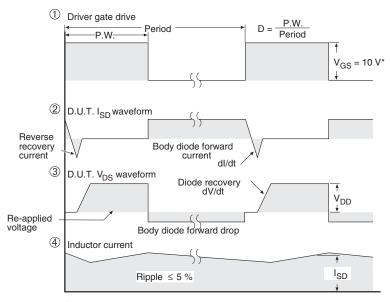


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit





* $V_{GS} = 5 V$ for logic level devices

Fig. 14 - For N-Channel

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